

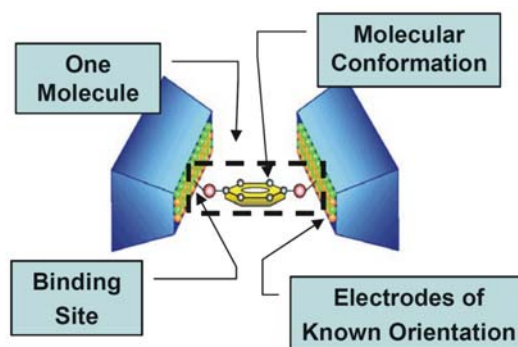
Scanning Probe Microscopy



C. Julian Chen, *Introduction to Scanning Tunneling Microscopy*

Department of Materials Science and Engineering, Northwestern University

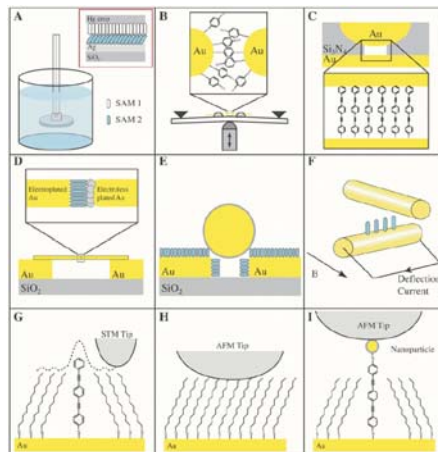
An Ideal Experiment for Probing Molecular Conduction



M. C. Hersam, *et al.*, *MRS Bulletin*, **29**, 385 (2004).

Department of Materials Science and Engineering, Northwestern University

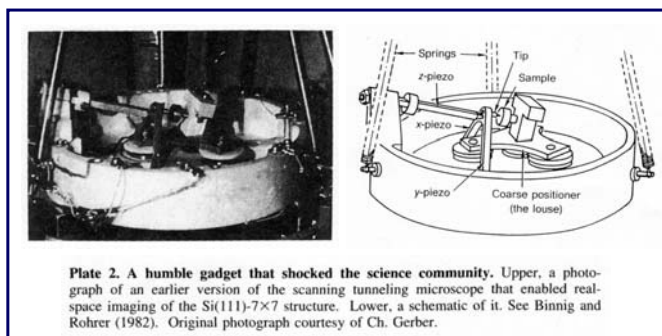
Real Experimental Strategies for Probing Molecular Conduction



B. A. Mantooth, *et al.*,
Proc. IEEE, **91**, 1785 (2003).

Department of Materials Science and Engineering, Northwestern University

The Scanning Tunneling Microscope (STM)

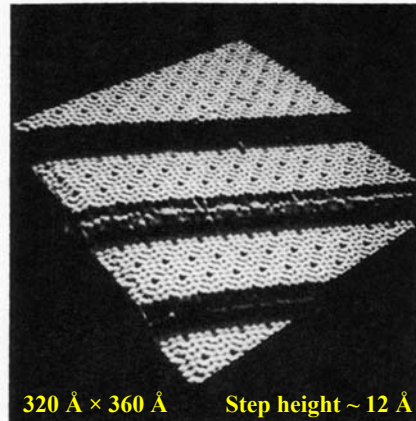


- STM invented by Gerd Binnig and Heinrich Rohrer in 1982
- Led to Nobel Prize in Physics, 1986

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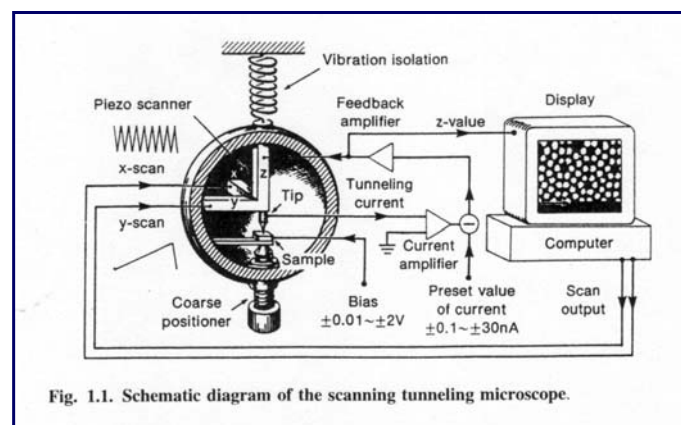
Si(111)-7×7: “Stairway to Heaven”



C. Julian Chen, *Introduction to Scanning Tunneling Microscopy*

Department of Materials Science and Engineering, Northwestern University

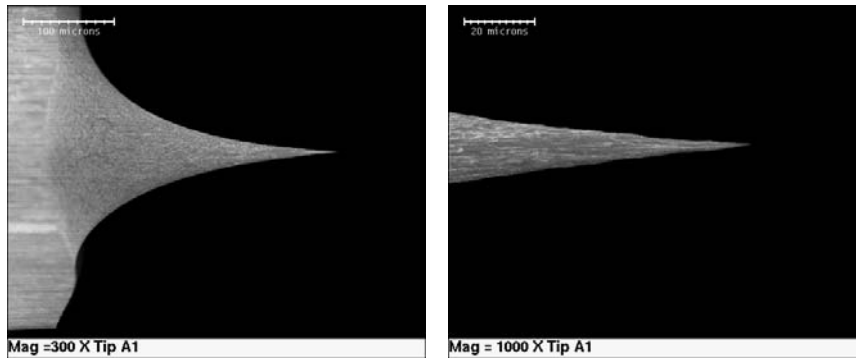
Scanning Tunneling Microscope Schematic



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Tungsten STM Tip



- Electrochemically etched using NaOH
- Ideally, the tip is atomically sharp

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One-Dimensional Tunnel Junction

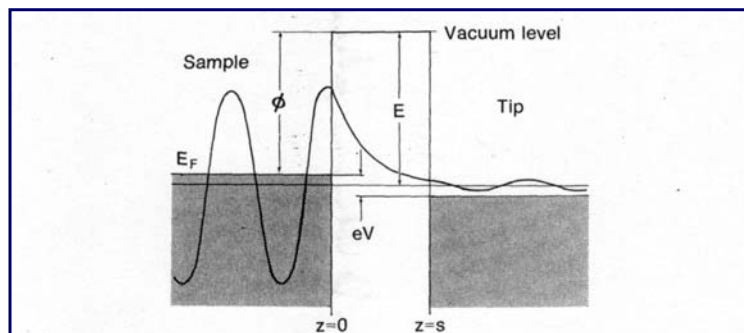


Fig. 1.4. A one-dimensional metal-vacuum-metal tunneling junction. The sample, left, and the tip, right, are modeled as semi-infinite pieces of free-electron metal.

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Tunneling Current – Approach #1

Assume metal-vacuum-metal junction, solve Schrödinger Equation:

$$I \propto V \rho_s e^{-2kW}, \text{ where } k = \frac{\sqrt{2m\phi}}{\hbar} = 0.51\sqrt{\phi(\text{eV})} \text{ \AA}^{-1}$$

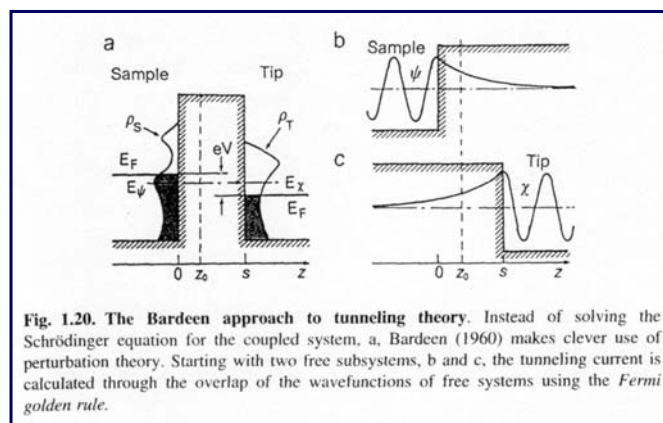
I = tunneling current ρ_s = local density of states of sample
 V = tip-sample voltage W = width of barrier

Typically, $\phi \sim 4 \text{ eV} \rightarrow k \sim 1 \text{ \AA}^{-1}$

\rightarrow Current decays by $e^2 \sim 7.4$ times per \AA

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Bardeen Tunneling Theory



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Tunneling Current – Approach #2

Consider overlap of wavefunctions from either side of barrier:

Using Fermi's Golden Rule (assuming $kT \ll$ energy resolution of the measurement),

$$I \propto \int_0^{eV} \rho_s(E_F - eV + \varepsilon) \rho_t(E_F + \varepsilon) d\varepsilon$$

sample
tip

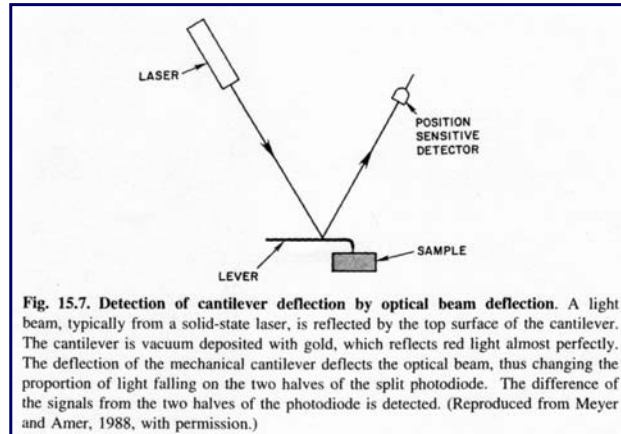
For a free electron metal tip, ρ_t is constant:

$$\frac{dI}{dV} \propto \rho_s(E_F - eV) \rightarrow \text{STM Spectroscopy}$$

Atomic Force Microscopy (AFM)

- Invented at Stanford by Binnig and Quate in 1986
- Bring tip-mounted micromachined cantilever into contact or close proximity of the surface
- “Atomic forces” deflect cantilever and is detected with laser deflection into a position sensitive photodiode
- Cantilever deflection is control signal for the feedback loop
- AFM can be done on “any surface” (i.e., conductive, insulating, semiconducting, biological, etc.) in “any environment” (i.e., air, vacuum, liquid, etc.)

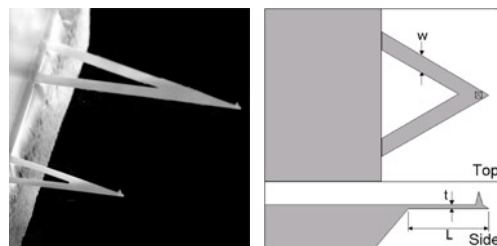
Force Detection with Optical Beam Deflection



C. Julian Chen, *Introduction to Scanning Tunneling Microscopy*

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Atomic Force Microscope Cantilevers



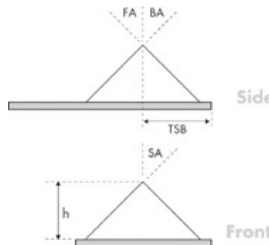
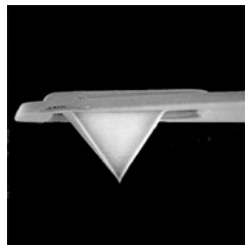
$$\begin{aligned} L &= 100 \mu\text{m} \\ w &= 20 \mu\text{m} \\ t &= 0.5 \mu\text{m} \end{aligned}$$

- Fabricated using conventional microfabrication procedures
- Backside coated with an optically reflective material (e.g., Au)

<https://www.veecoprobes.com/>

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Atomic Force Microscope Tips



$h = 3 \mu\text{m}$
Angles = 35°

- Typical radius of curvature is $\sim 10 \text{ nm}$
- Tips are often coated with conductive materials, magnetic materials, low wear materials, or organic/biological molecules.

<https://www.veecoprobes.com/>

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Fluid Cell for Atomic Force Microscopy

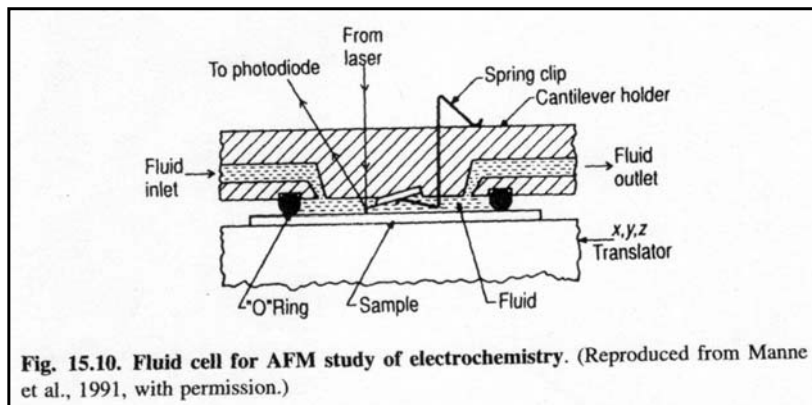


Fig. 15.10. Fluid cell for AFM study of electrochemistry. (Reproduced from Manne et al., 1991, with permission.)

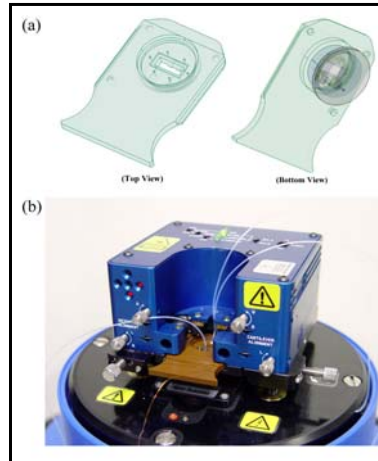
C. Julian Chen, *Introduction to Scanning Tunneling Microscopy*

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AFM Photographs



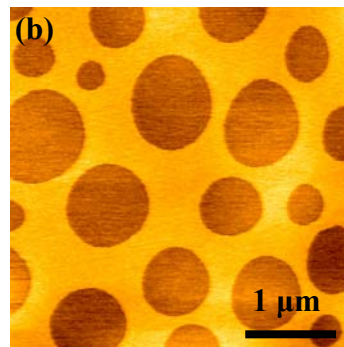
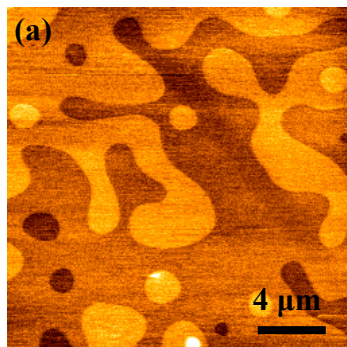
Thermomicroscopes
CP Research AFM



Custom Liquid Cell

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AFM Images of Hematite

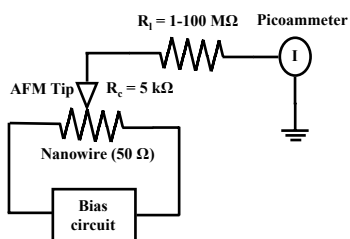


- Measured atomic step height of 2.2 \AA
- Vertical spatial resolution of $\sim 0.1 \text{ \AA}$ in air.

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Contact Mode AFM Potentiometry

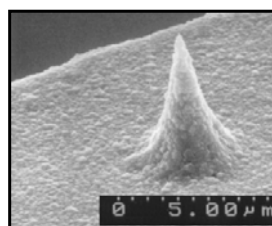
Experimental setup:



Requirements of AFM tip:

- Conductive tip with small R_c (k Ω range).
- Low R_c must be sustained after extensive scanning in contact mode.

Conductive diamond coated Si tips provide $R_c = 5 \text{ k}\Omega$ with low wear at a repulsive force of $0.54 \text{ }\mu\text{N}$.



Resolution requirements:

To analyze nanowire failure,

- Spatial resolution < 10 nm
- Voltage sensitivity < 100 μV

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Noncontact vs. Contact AFM Potentiometry

Noncontact mode:

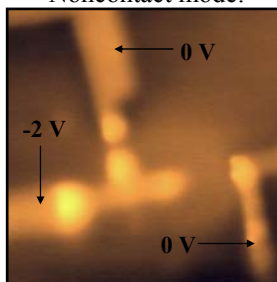


Image size = (1000 nm)²

Contact mode:

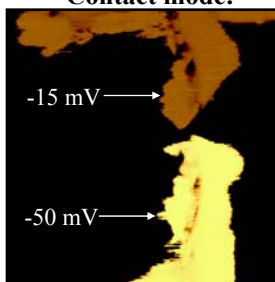


Image size = (500 nm)²

Contact mode:

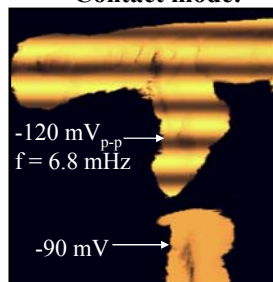


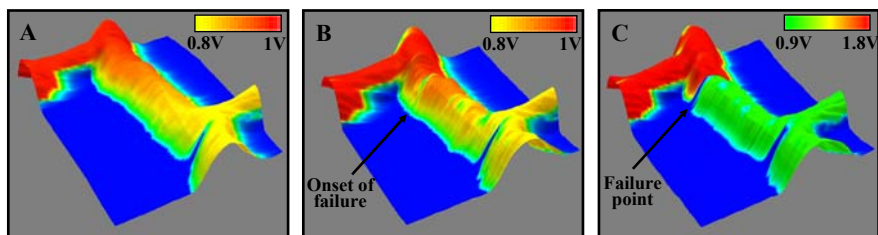
Image size = (500 nm)²

- Noncontact mode AFM potentiometry possesses **~50 mV** potential sensitivity and **~50 nm** spatial resolution.
- Contact mode AFM potentiometry possesses **~1 μV** potential sensitivity, **~5 nm** spatial resolution, and **~0.01 ms** time response.

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AFM Potentiometry of Nanowire Failure

Evolution of nanowire failure:

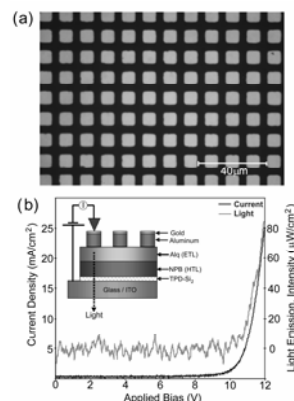
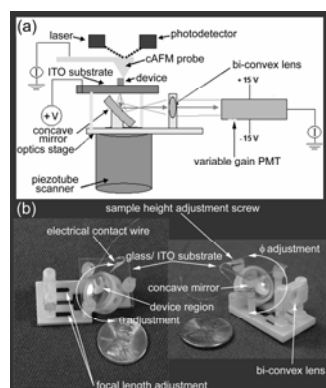


Contact mode AFM potentiometry images: Wire width = 60 nm
(Breakdown current density = 3.75×10^{12} A/m²).

M. C. Hersam, *et al.*, *Appl. Phys. Lett.*, **72**, 915 (1998).

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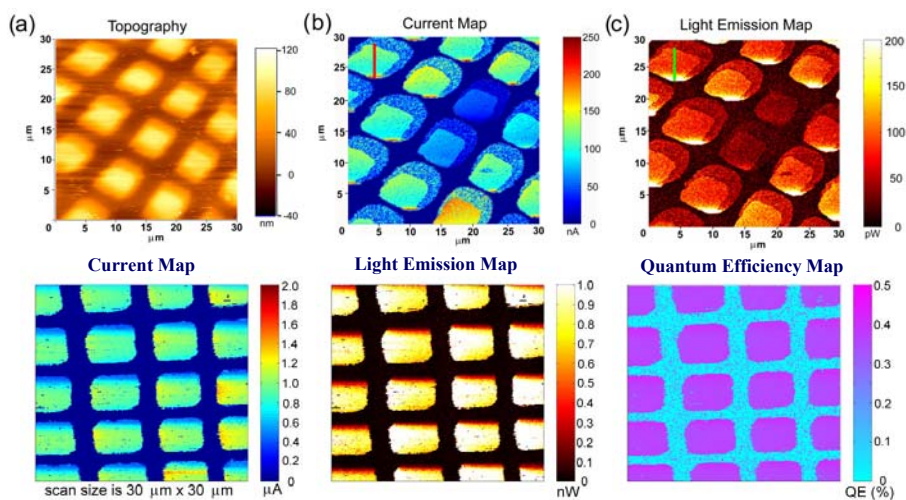
Atomic Force Electroluminescence Microscopy



L. S. C. Pingree, *et al.*, *Appl. Phys. Lett.*, **85**, 344 (2004).

Department of Materials Science and Engineering, Northwestern University

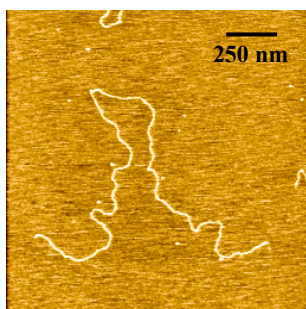
AFEM on Organic LED Arrays



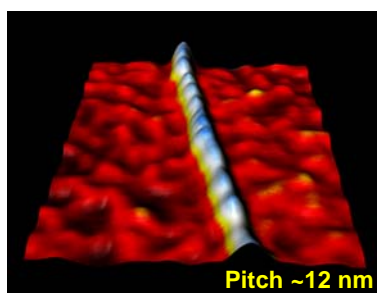
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“Single Molecule Imaging” with Ambient AFM

DNA Molecules



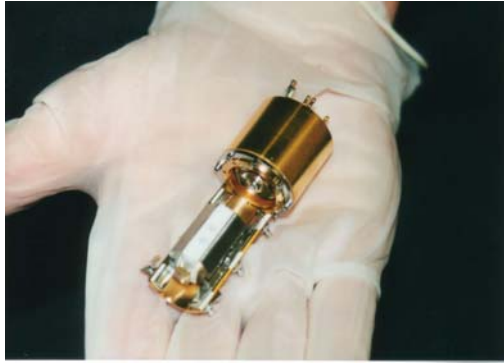
DNA Wrapped SWNTs



Typical ambient AFM resolution is ~ 10 nm as opposed to atomic resolution for STM \rightarrow STM is typically the technique of choice for intramolecular spatial resolution imaging

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Example Ultra-high Vacuum (UHV) STM Design



- Homebuilt STM in the Hersam lab at Northwestern University
- STM is a modified Lyding scanner

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Scanner Construction: Piezotubes

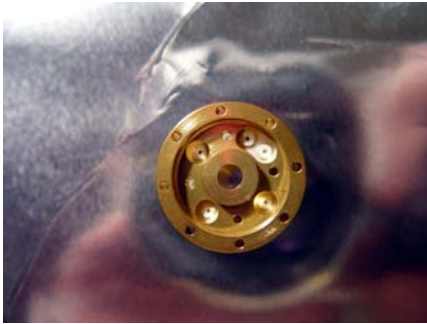
Outer tube:
0.650" OD
0.570" ID
0.750" Long



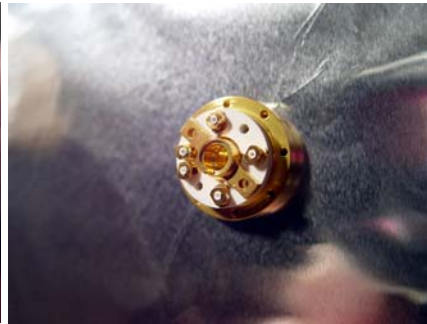
Inner tube:
0.375" OD
0.315" ID
0.750" Long

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Scanner Construction: Base Plug



Front View



Rear View

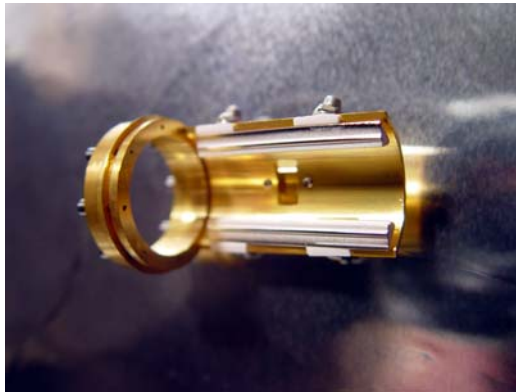
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Scanner Construction: Piezotubes Soldered into Base Plug



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Scanner Construction: Course Translation Platform



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Scanner Construction: Course Translation Platform Soldered onto Outer Piezotube



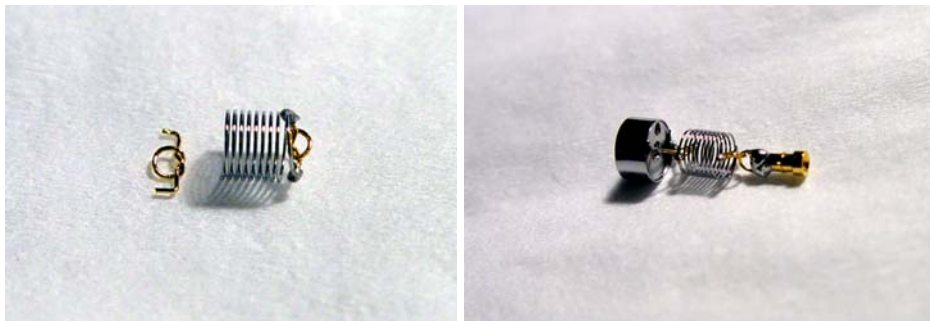
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Scanner Construction: End Cap Positioned onto Inner Piezotube



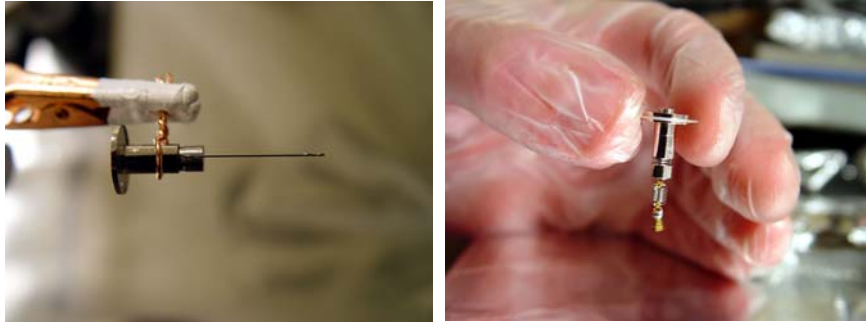
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Scanner Construction: Tip Contact Assembly



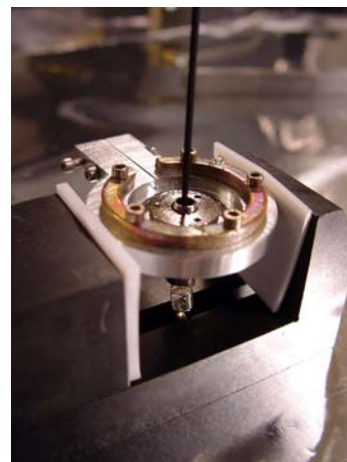
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Scanner Construction: Full Tip Assembly



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Scanner Construction: Adjusting Clamping Force on Sapphire Washer and Soldering into Inner Piezotube End Cap



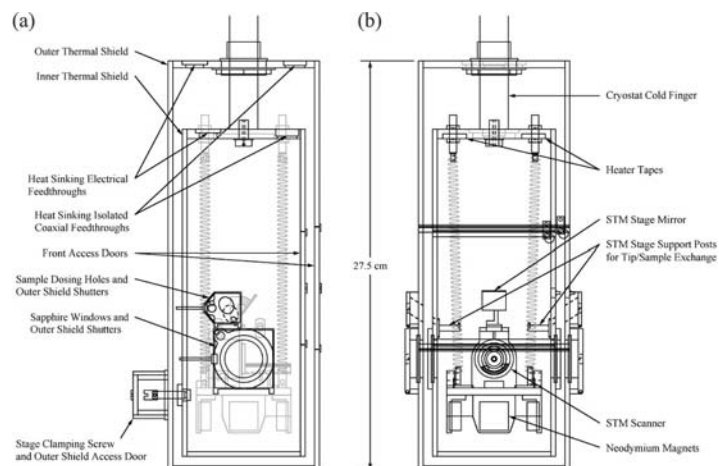
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Scanner Complete



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Cryogenic Variable Temperature UHV STM



E. T. Foley, *et al.*, *Rev. Sci. Instrum.*, **75**, 5280 (2004).

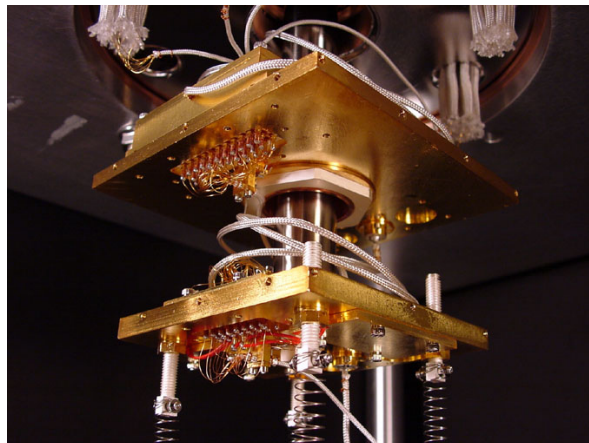
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Vibration Isolation



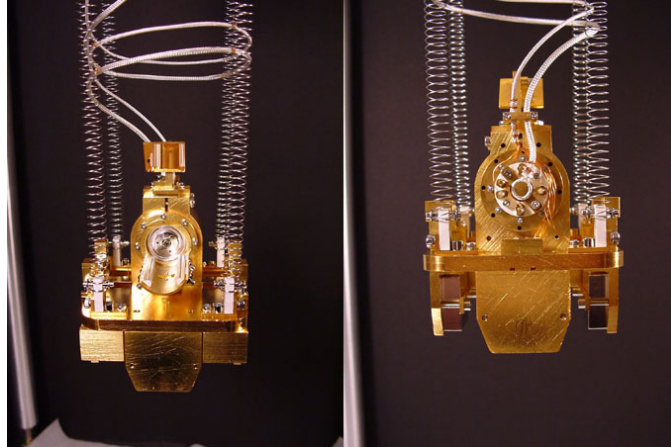
Department of Materials Science and Engineering, Northwestern University

Detail of Roof Plate



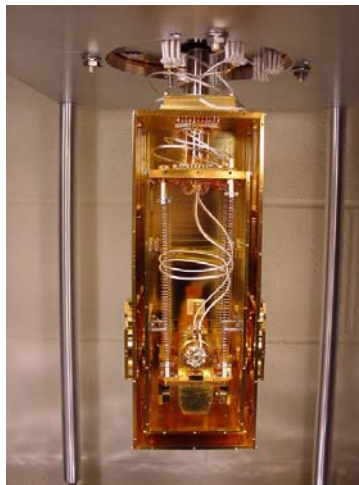
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Detail of STM Stage



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Thermal Shields with Back Panel Removed



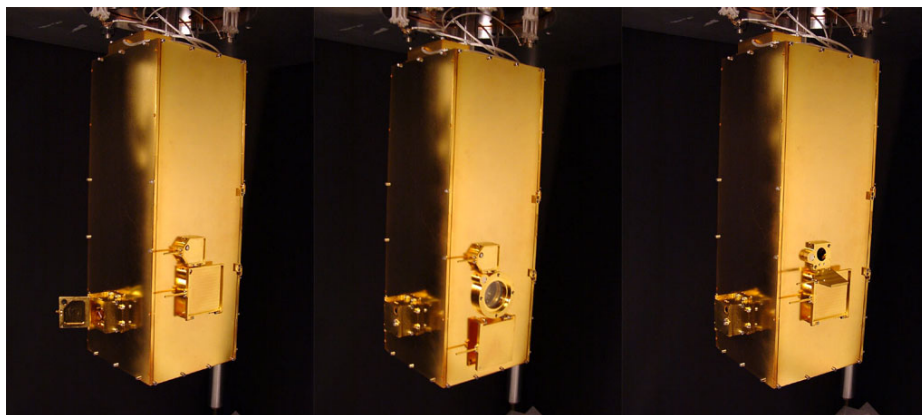
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Stage Locking Screw for Cooldown



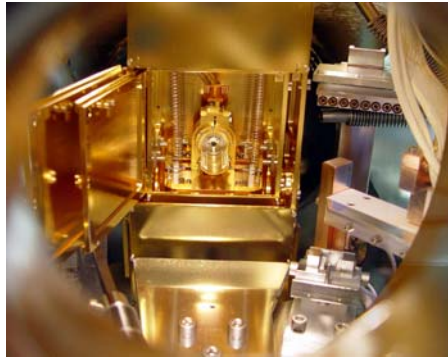
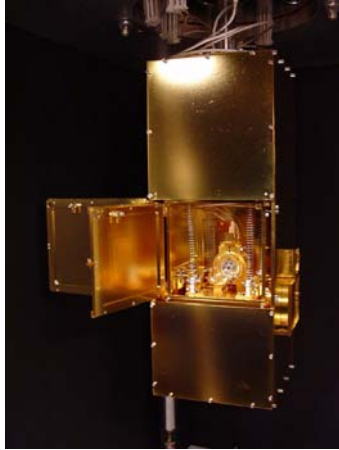
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Rear Door and Shutter Action



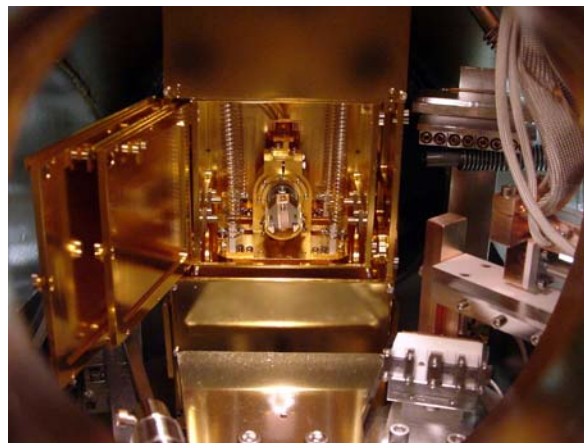
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Front Doors Open for STM Access



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Sample and Probe Mounted for Scanning



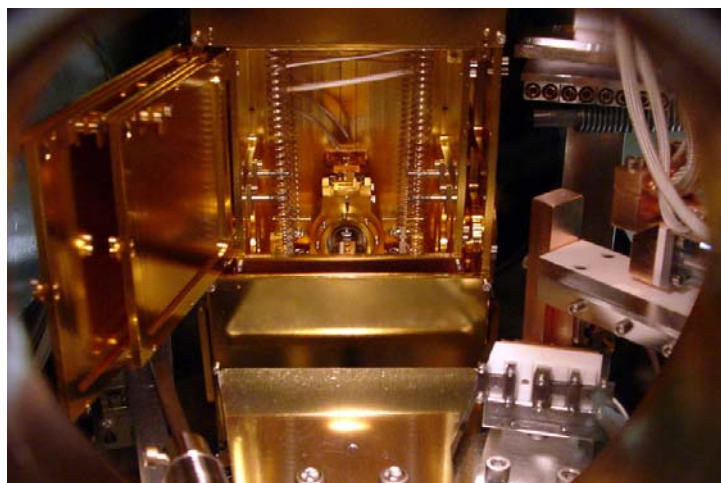
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Mirror Allows for Top-Down View of Tip-Sample Junction



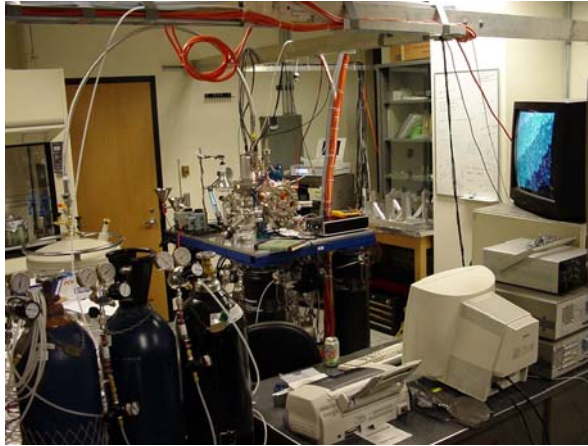
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STM Suspended for Scanning



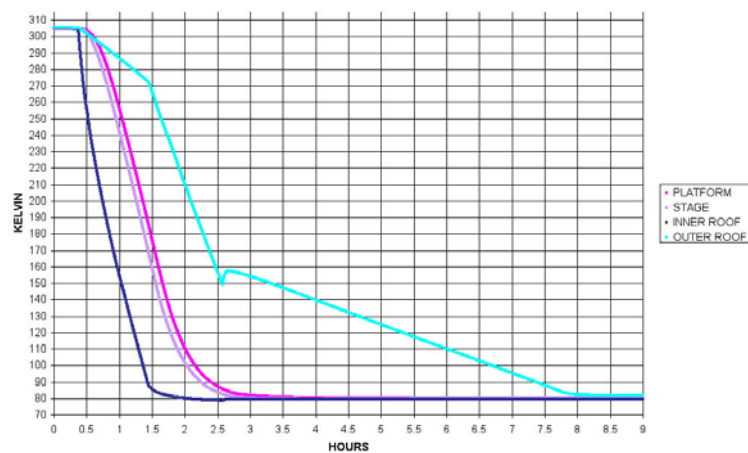
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UHV Chamber and Liquid Helium Dewar



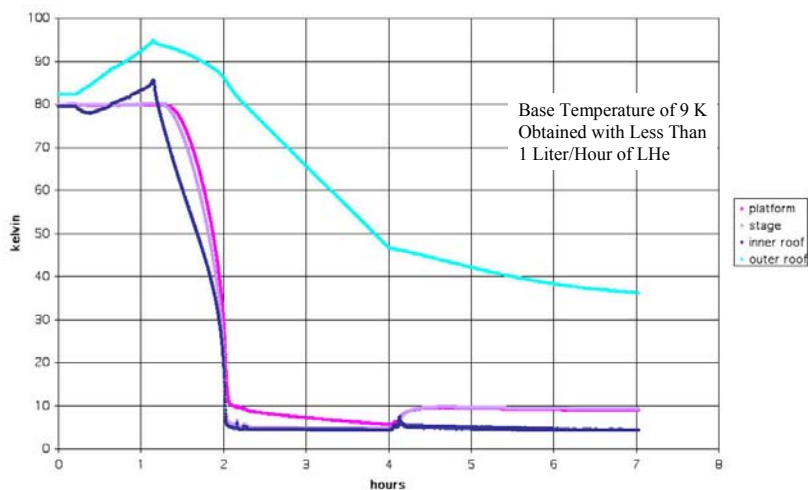
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Cooling with Liquid Nitrogen



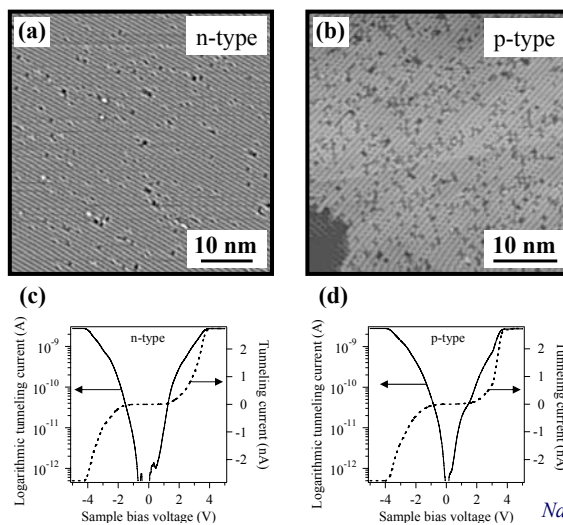
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Cooling with Liquid Helium



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Degenerately Doped Si(100) Surfaces



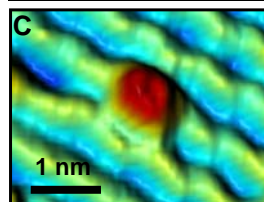
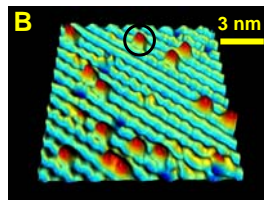
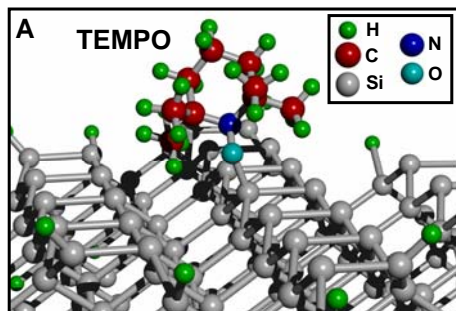
N. P. Guisinger, *et al.*,
Nanotechnology, **15**, S452 (2004).

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TEMPO on the Si(100)-2×1 Surface

N. P. Guisinger, *et al.*, *Nano Lett.*, **4**, 55 (2004).

TEMPO:
(2,2,6,6-tetramethyl-1-piperidinyloxy)

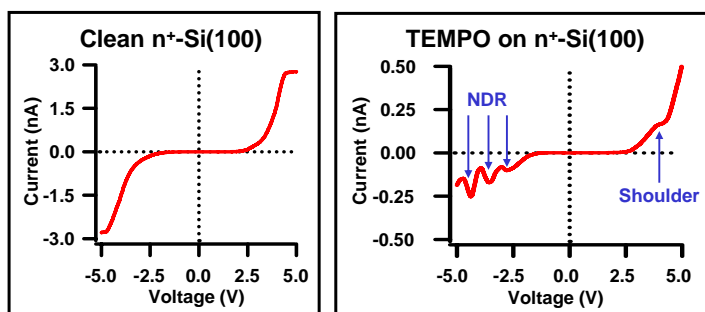


Individual TEMPO molecules are probed with the STM

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I-V Curve for TEMPO on n⁺-Si(100)

N. P. Guisinger, *et al.*, *Nano Lett.*, **4**, 55 (2004).

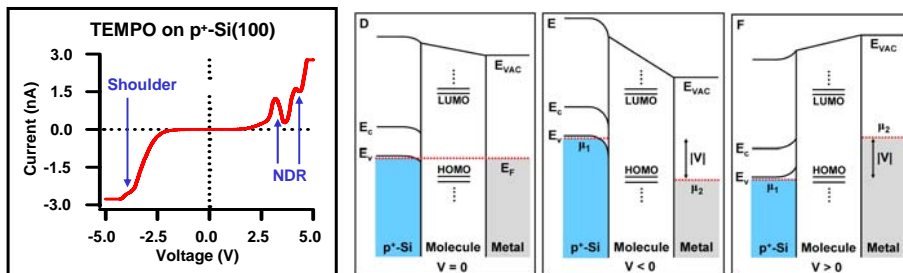


- NDR events are only observed at negative sample bias.
- Shoulder is only observed at positive sample bias.
- NDR bias values depend sensitively on tip-sample spacing
- NDR is observed in both bias sweep directions

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I-V Curve for TEMPO on p⁺-Si(100)

N. P. Guisinger, *et al.*, *Nano Lett.*, **4**, 55 (2004).

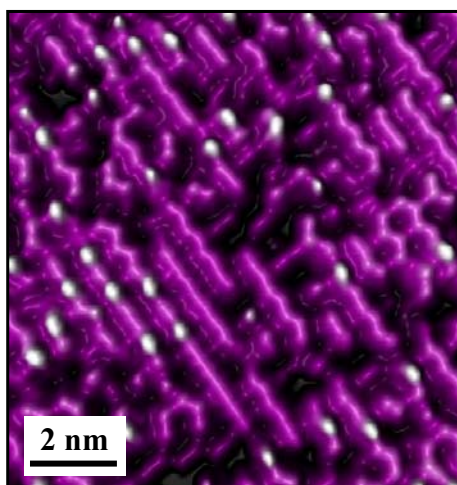


Equilibrium Shoulder NDR

- Qualitatively similar behavior to TEMPO on n⁺-Si(100) except opposite polarity.
- Orbital energy shift may be due to charge transfer with the substrate.

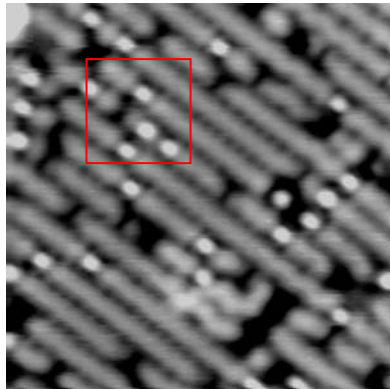
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Si(100) Dosed with Cyclopentene at 80 K

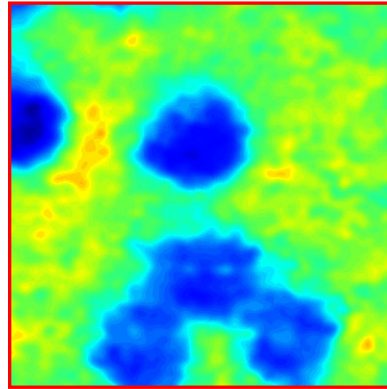


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dI/dV Imaging of Cyclopentene on Si(100) at 80 K



150 Å x 150 Å, -2.15 V, 0.1 nA

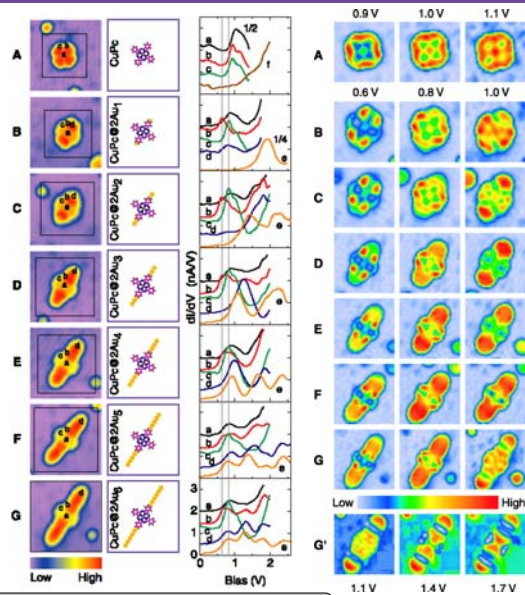


dI/dV Map at -2.8 V

Department of Materials Science and Engineering, Northwestern University

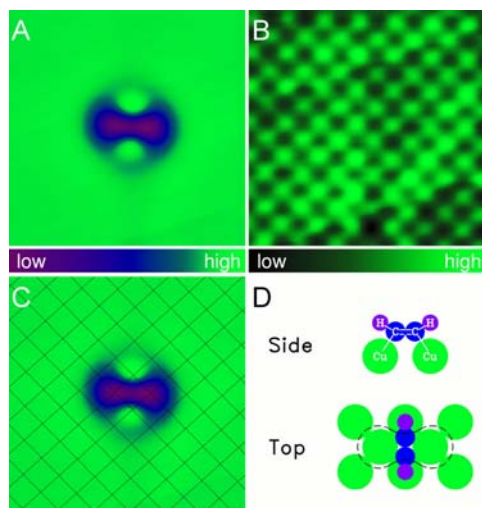
STM Spectroscopy: CuPc and Au Nanoelectrodes on NiAl(110)

G. V. Nazin, *et al.*,
Science, **302**, 77 (2003).



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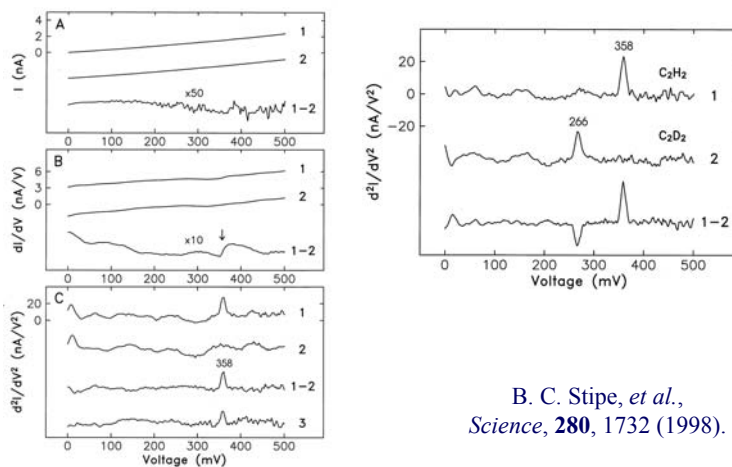
C_2H_2 on Cu(100)



B. C. Stipe, *et al.*,
Science, **280**, 1732 (1998).

Department of Materials Science and Engineering, Northwestern University

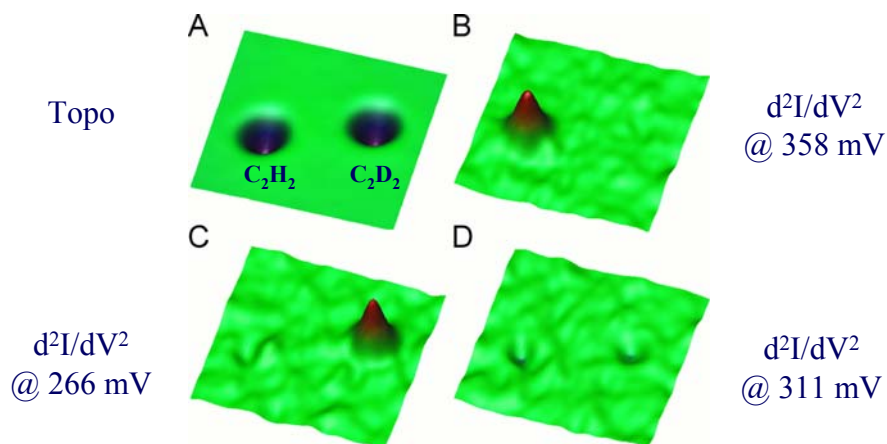
Inelastic Electron Tunneling Spectroscopy



B. C. Stipe, *et al.*,
Science, **280**, 1732 (1998).

Department of Materials Science and Engineering, Northwestern University

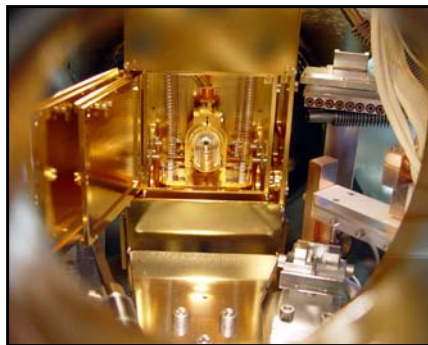
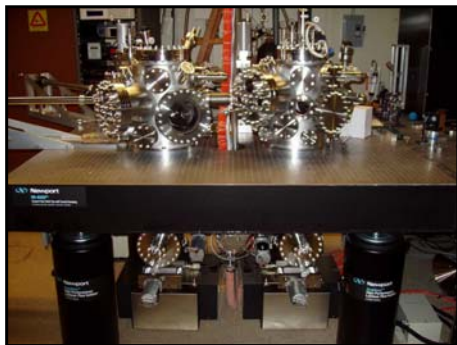
Spatial Maps of d^2I/dV^2



B. C. Stipe, *et al.*, *Science*, **280**, 1732 (1998).

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Tip Enhanced Raman Spectroscopy



- TERS is an alternative strategy for single molecule vibrational spectroscopy
- UHV TERS is currently being constructed at Northwestern University.

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